

**Search Notes**

Application/Control No.

10/664,936

Examiner

Cheukfan Lee

Applicant(s)/Patent under  
Reexamination

HUANG ET AL.

Art Unit

2625

**SEARCHED**

| Class | Subclass            | Date      | Examiner |
|-------|---------------------|-----------|----------|
| 358   | 475,509,<br>474,497 | 9/15/2006 | C.L.     |
|       | 483,482             |           |          |
|       | 471,494             |           |          |
|       | 473,472             |           |          |
|       | 512-514             |           |          |
|       | 505,506             |           |          |
|       | 487,484             |           |          |
| 382   | 312,313             |           |          |
|       | 318,319             |           |          |
| 250   | 208.1,216           |           |          |
|       | 239                 |           |          |
|       | 234-236             |           |          |
| 359   | 212                 |           |          |
| 355   | 67,68               |           |          |

**INTERFERENCE SEARCHED**

| Class | Subclass | Date      | Examiner |
|-------|----------|-----------|----------|
| 358   | 474      | 9/15/2006 | C.L.     |
|       | 475      |           |          |
|       | 497      |           |          |
|       |          |           |          |

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

|   | DATE      | EXMR |
|---|-----------|------|
| EAST search: search terms include:<br>light\$3 with ((plural\$5 series row<br>multiple) adj3 (slit pinhole (pin adj<br>hole) aperture | 9/15/2006 | C.L. |
| (search terms cont.):<br>hole))   |           |      |
| Inventor search   |           |      |
| Reference only:<br>Fujimoto et al. (6,376,822), Fig. 7, a<br>plurality of through-hole 43a (3 of them<br>) for R, G and B             |           |      |
| My related case 10/256,425  |           |      |
|   |           |      |
|   |           |      |
|   |           |      |